Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

2SK2542

Switching Regulator Applications

• 4-V gate drive

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & :\ RDS\ (ON) = 0.75\ \Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & :\ |\ Y_{fs}| = 7.0\ S\ (typ.) \\ \bullet & Low\ leakage\ current & :\ IDSS = 100\ \mu A\ (max)\ (VDS = 500\ V) \\ \bullet & Enhancement\ mode & :\ V_{th} = 2.0{\sim}4.0\ V\ (VDS = 10\ V,\ ID = 1\ mA) \end{array}$

Absolute Maximum Ratings (Ta = 25°C)

| Characteris | stics | Symbol | Rating | Unit | |
|--|----------------|------------------|---------|------|--|
| Drain-source voltage | | V_{DSS} | 500 | V | |
| Drain-gate voltage (R _{GS} = 20 kΩ) | | V_{DGR} | 500 | ٧ | |
| Gate-source voltage | | V _{GSS} | ±30 | V | |
| Drain current | DC (Note 1) | I _D | 8 | Α | |
| | Pulse (Note 1) | I _{DP} | 32 | А | |
| Drain power dissipation | n (Tc = 25°C) | P_{D} | 80 | W | |
| Single pulse avalanche energy (Note 2) | | E _{AS} | 312 | mJ | |
| Avalanche current | | I _{AR} | 8 | А | |
| Repetitive avalanche e | nergy (Note 3) | E _{AR} | 8 | mJ | |
| Channel temperature | | T _{ch} | 150 | °C | |
| Storage temperature range | | T _{stg} | -55~150 | °C | |

10.3MAX. 63.6±0.2

10.3MAX. 70.76

10.3MAX. 70.7

Weight: 2.0 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

| Characteristics | Symbol | Max | Unit |
|--|------------------------|------|------|
| Thermal resistance, channel to case | R _{th (ch-c)} | 1.56 | °C/W |
| Thermal resistance, channel to ambient | R _{th (ch-a)} | 83.3 | °C/W |

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 8.3 mH, R_G = 25 Ω , I_{AR} = 8 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



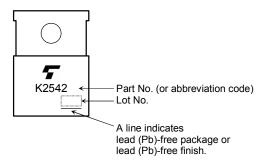
Electrical Characteristics (Ta = 25°C)

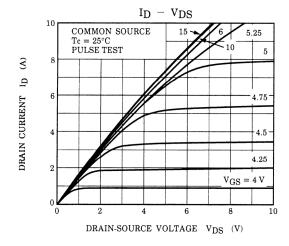
| Charac | cteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|-----------------|-----------------------|---|-----|------|------|------|
| Gate leakage cu | ırrent | I _{GSS} | V _{GS} = ±25 V, V _{DS} = 0 V | _ | _ | ±10 | μΑ |
| Gate-source bro | eakdown voltage | V (BR) GSS | $I_{G} = \pm 10 \mu A, V_{GS} = 0 V$ | ±30 | _ | _ | V |
| Drain cut-off cu | rrent | I _{DSS} | V _{DS} = 500 V, V _{DS} = 0 V | _ | _ | 100 | μA |
| Drain-source br | eakdown voltage | V _{(BR) DSS} | I _D = 10 mA, V _{GS} = 0 V | 500 | _ | _ | V |
| Gate threshold | voltage | V_{th} | V _{DS} = 10 V, I _D = 1 mA | 2.0 | _ | 4.0 | V |
| Drain-source O | N resistance | R _{DS (ON)} | V _{GS} = 10 V, I _D = 4 A | _ | 0.75 | 0.85 | Ω |
| Forward transfe | r admittance | Y _{fs} | V _{DS} = 10 V, I _D = 4 A | 3.5 | 7.0 | _ | S |
| Input capacitano | ce | C _{iss} | | _ | 1300 | _ | pF |
| Reverse transfe | r capacitance | C _{rss} | V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz | _ | 130 | _ | |
| Output capacitance | | Coss |] | _ | 400 | _ | |
| Switching time | Rise time | t _r | $V_{GS} \stackrel{10 \text{ V}}{\text{0 V}} \stackrel{\text{I}_{D} = 4 \text{ A}}{\text{0 V}_{out}} \stackrel{\text{V}_{out}}{\text{0 V}} \stackrel{\text{RL}}{\text{0 V}} = 50 \Omega$ | _ | 26 | _ | |
| | Turn-on time | t _{on} | | l | 45 | ı | ns |
| | Fall time | t _f | | l | 40 | l | 115 |
| | Turn-off time | t _{off} | Duty $\leq 1\%$, $t_{\rm w} = 10 \mu \rm s$ | ı | 140 | | |
| Total gate charge (Gate-source plus gate-drain) | | Qg | | _ | 30 | _ | |
| Gate-source charge | | Q _{gs} | $V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$ | | 17 | | nC |
| Gate-drain ("miller") charge | | Q_{gd} | | | 13 | | |

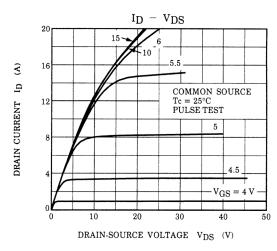
Source-Drain Ratings and Characteristics (Ta = 25°C)

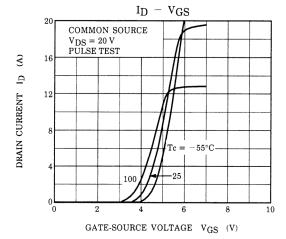
| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|------------------|--|-----|------|------|------|
| Continuous drain reverse current (Note 1) | I _{DR} | _ | _ | _ | 8 | Α |
| Pulse drain reverse current (Note 1) | I _{DRP} | _ | _ | _ | 32 | Α |
| Forward voltage (diode) | V _{DSF} | I _{DR} = 8 A, V _{GS} = 0 V | _ | _ | -1.7 | V |
| Reverse recovery time | t _{rr} | I _{DR} = 8 A, V _{GS} = 0 V dI _{DR} / dt = 100 A / μs | _ | 1200 | _ | ns |
| Reverse recovery charge | Q _{rr} | dl _{DR} / dt = 100 A / μs | - 1 | 10 | _ | μC |

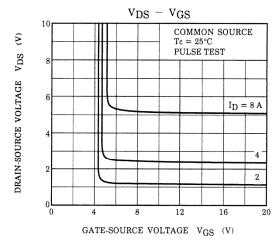
Marking

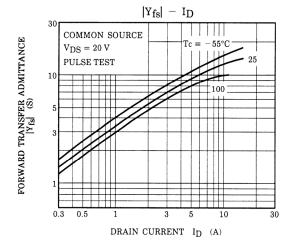


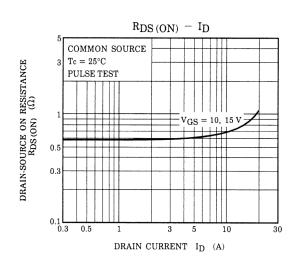


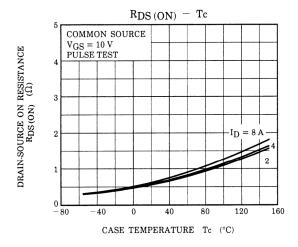


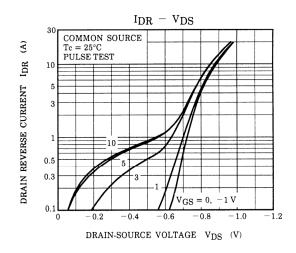


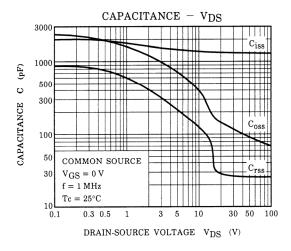


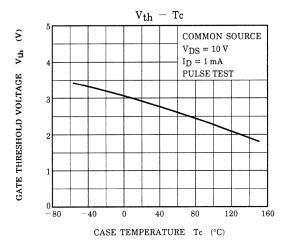


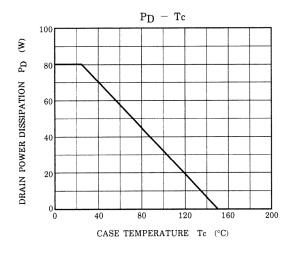


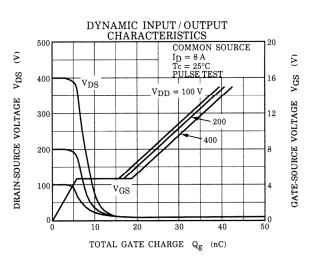




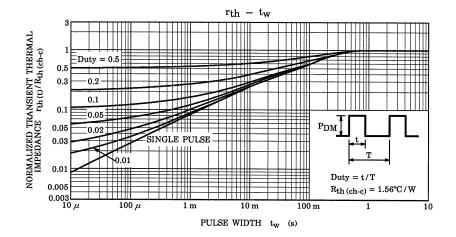


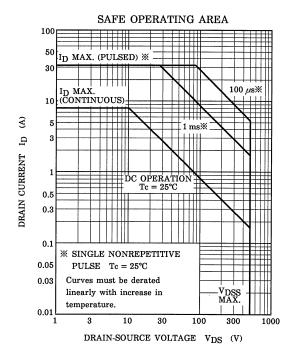


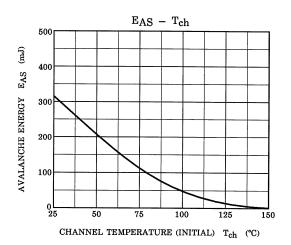


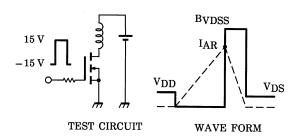


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$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 90~V,~L = 8.3~mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VI} \right) \cdot \frac{1}{2} \cdot \frac{$$

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